Metadata for parallel beam XRD measurements for USGS EMIT mineral data on rock chip surfaces:

The data collection parameters are:

Rigaku SmartLab Diffractometer

Cu K alpha sealed tube source 40 kV 40 mA

One dimensional solid state Rigaku Dtex detector, with Ni foil Cu K beta filter

5 degree source and detector Soller slits

10 mm wide incident beam slit

2/3 degree incident bean divergence slit

Data collected at 6 degrees/minute, 0.02 degrees step size

Data collection range 3-150 degrees two theta